ESH-Friendly Cleaning and Rinsing of Multi-

1

Material Surfaces and Structures

(Task Number: : 425.043)

Manish Keswani¹, Srini Raghavan¹, Farhang Shadman²

¹Material Science and Engineering Department ²Chemical and Environmental Engineering Department

> ERC Annual Review Meeting March 2012

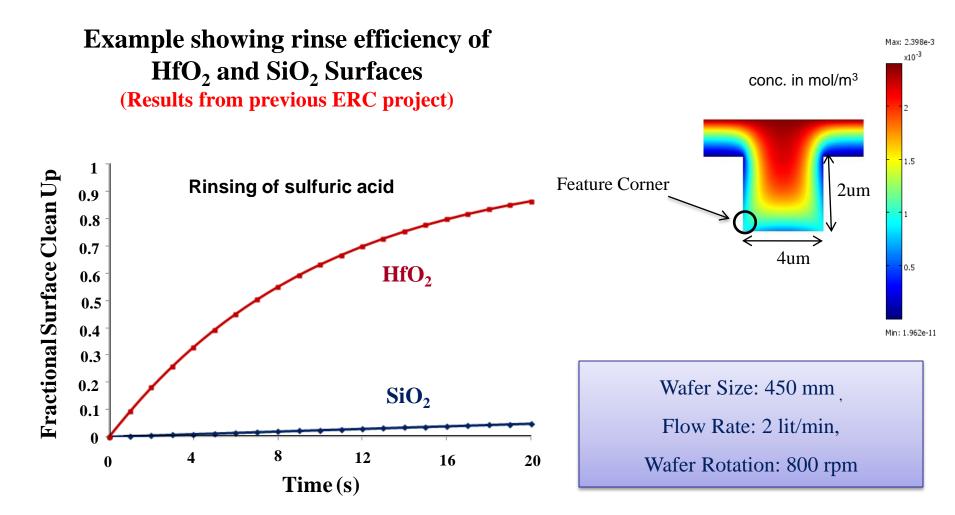
<u>Challenges in Cleaning and Rinsing of</u> <u>Multi-Material Surfaces and Structures</u>

Fabrication of current state of the art devices requires cleaning and rinsing of sub-micron size structures

> The complexities in rinsing of these structures arise from:

- Differences in wettability of various surfaces
- Inhibited rinsing in regions with lower wettability and contributions to watermark and post rinse residues
- Slow transport of cleaning chemicals and rinsing water in and out of the structures
- Impurity retention due to surface interactions and surface charge effects
- The conventional rinsing processes have not been designed based on the rinse process bottlenecks and lack in-situ and real-time monitoring

Effect of Surface Characteristics on Rinsing Effectiveness



Different dielectric materials have significantly different impurity retention, rinsing dynamics, and cleaning efficiency

Objective and Method of Approach

Objective:

- Understand the bottleneck of the rinse process involving small structures that consist of different materials
- Develop innovative methods to enhance the rinsing process

Method of Approach:

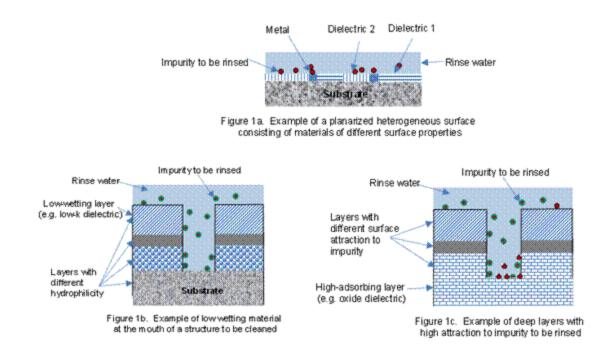
- Subtask 1: In-Situ and Real-Time Investigation of Rinsing of Multi-Material Structures
- Subtask 2: Megasonic Enhancement of the Rinsing Process
- Subtask 3: Process Simulation and Optimized Low-Water Rinse Recipe Development

ESH Impact

Robust and efficient rinse processes would have a major ESH impact by reducing the usage of water and energy

Subtask 1: In-Situ and Real-Time Investigation of Rinsing of Multi-Material Patterned Wafers

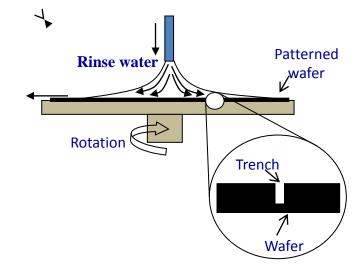
Test structures equipped with real-time and in-situ monitoring sensors will be designed, fabricated, and used.



Subtask 1: In-Situ and Real-Time Investigation of Rinsing of Multi-Material Patterned Wafers

Unique experimental single-wafer spin tool equipped with real-time impedance spectroscopy probe will be used to investigate:

- The dynamics of rinse process
- The bottleneck of the process in terms of location and type of surface/material
- The role of key operational parameters
- The significance of wettability and fluid penetration in nano-structures



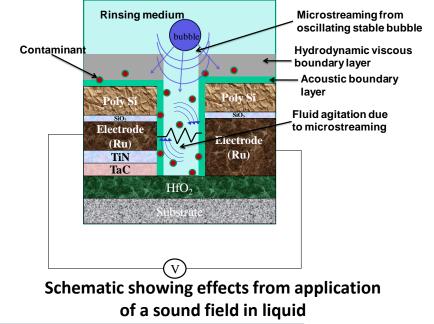


Subtask 2: Megasonic enhancement of the rinsing process

Application of megasonic field can cause significant microstreaming and improved mass transport of contaminants

The use of megasonic energy in improving the mass transport of contaminants out of the narrow trenches and enhancing the overall rinse efficiency will be explored
Wirrow

Effect of power density and solution variables (temperature, dissolved gas content) on rinsing efficiency and feature damage will be investigated



Subtask 3: Process Simulation and Optimized Low-Water Rinse Recipe Development

Development of a Rinse Model (incorporating flow due to convection, diffusion, acoustic field and surface effects including adsorption/desorption)

To analyze the rinse data

To facilitate the development of new and efficient rinse process

Model will include

Effects of surface charging, surface adsorption and desorption characteristics, and surface wettabilities of different films

***** Enhancement effects of megasonic application and rinsing process

Process model will be validated with the direct measurements and used for study of process operation parameters and low-water recipe development

Timeline and Deliverables

Fabricate heterogeneous multi-material rinse test structures Q1-2 (2012)

Conduct rinsing experiments using the test structures to identify key solution and process variables that affect rinsing performance Q2-4 (2012)

Solution Solution

Evaluate effect of sound field in improving the rinse efficiency Q2-4 (2013)

Timeline and Deliverables

Carry out damage studies on test structures and indentify conditions that reduce damage while maintaining rinse efficiency Q1-2 (2014)

Solution State And Stat

Optimize and develop a single wafer process that is capable of providing significantly improved damage-free rinsing performance Q3-4 (2014)

Planned Interactions and Cost Sharing

□ Fab level tests to verify rinsing data obtained at U of A will be carried out in collaboration with the *Freescale group* (coordinated by Hsi-An Kwong), and *Samsung Electronics* (Jeongnam Han and Kuntack Lee)

□ Technical meetings will be held with contacts from *TEL* (Ian Brown), *Micron* (Niraj Rana), *Global Foundries* (Akshey Sehgal) to discuss progress of the project and any deviations needed to be in-line with the industry standards.

\$30k/year committed cost sharing from UA and AZ/ TRIF Program

SRC Engineering Research Center for Environmentally Benign Semiconductor Manufacturing